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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	18432
Number of I/O	71
Number of Gates	60000
Voltage - Supply	1.425V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 125°C (TA)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a3p060-1vq100t

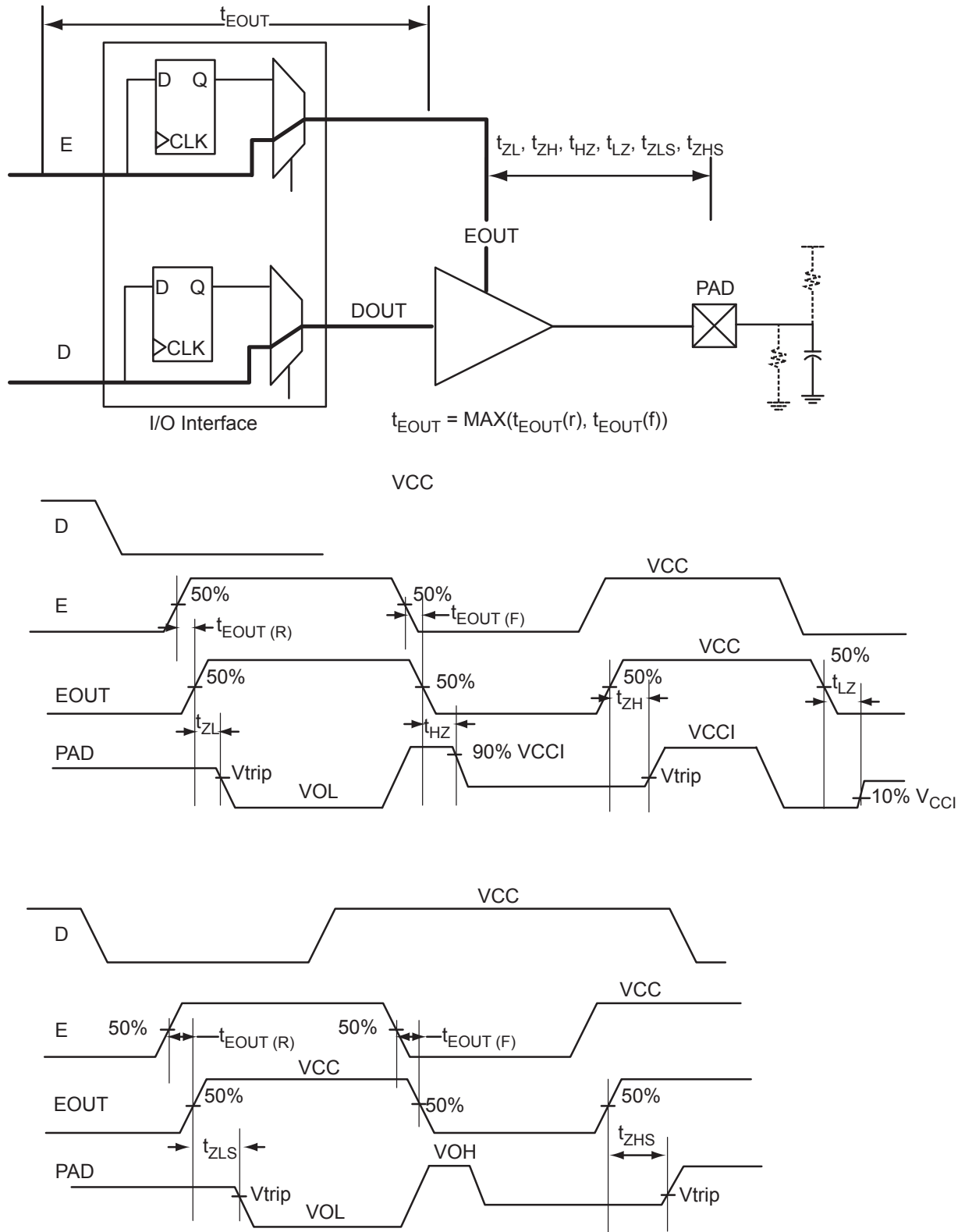


Figure 2-6 • Tristate Output Buffer Timing Model and Delays (example)

Single-Ended I/O Characteristics

3.3 V LVTTL / 3.3 V LVCMOS

Low-Voltage Transistor–Transistor Logic (LVTTL) is a general-purpose standard (EIA/JESD) for 3.3 V applications. It uses an LVTTL input buffer and push-pull output buffer.

Table 2-32 • Minimum and Maximum DC Input and Output Levels
Applicable to Advanced I/O Banks

3.3 V LVTTL / 3.3 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IosL	IosH	IIL	IiH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
2 mA	−0.3	0.8	2	3.6	0.4	2.4	2	2	27	25	10	10
4 mA	−0.3	0.8	2	3.6	0.4	2.4	4	4	27	25	10	10
6 mA	−0.3	0.8	2	3.6	0.4	2.4	6	6	54	51	10	10
8 mA	−0.3	0.8	2	3.6	0.4	2.4	8	8	54	51	10	10
12 mA	−0.3	0.8	2	3.6	0.4	2.4	12	12	109	103	10	10
16 mA	−0.3	0.8	2	3.6	0.4	2.4	16	16	127	132	10	10
24 mA	−0.3	0.8	2	3.6	0.4	2.4	24	24	181	268	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 125°C junction temperature.
3. Software default selection highlighted in gray.

Table 2-33 • Minimum and Maximum DC Input and Output Levels
Applicable to Standard Plus I/O Banks

3.3 V LVTTL / 3.3 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IosL	IosH	IIL	IiH
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA ¹	Max. mA ¹	μA ²	μA ²
2 mA	−0.3	0.8	2	3.6	0.4	2.4	2	2	27	25	10	10
4 mA	−0.3	0.8	2	3.6	0.4	2.4	4	4	27	25	10	10
6 mA	−0.3	0.8	2	3.6	0.4	2.4	6	6	54	51	10	10
8 mA	−0.3	0.8	2	3.6	0.4	2.4	8	8	54	51	10	10
12 mA	−0.3	0.8	2	3.6	0.4	2.4	12	12	109	103	10	10
16 mA	−0.3	0.8	2	3.6	0.4	2.4	16	16	109	103	10	10

Notes:

1. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
2. Currents are measured at 125°C junction temperature.
3. Software default selection highlighted in gray.

Timing Characteristics

Table 2-46 • 2.5 V LVCMOS High Slew

Automotive-Case Conditions: $T_J = 135^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 2.3\text{ V}$
Applicable to Advanced I/O Banks

Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	STD	0.64	9.69	0.05	1.45	0.46	8.76	9.69	1.48	1.25	11.26	12.187	ns
	-1	0.55	8.24	0.04	1.23	0.39	7.45	8.24	1.48	1.25	9.58	10.367	ns
6 mA	STD	0.64	5.78	0.05	1.45	0.46	5.63	5.78	1.68	1.62	8.13	8.277	ns
	-1	0.55	4.91	0.04	1.23	0.39	4.79	4.91	1.69	1.63	6.92	7.04	ns
12 mA	STD	0.64	3.98	0.05	1.45	0.46	4.05	3.84	1.82	1.86	6.55	6.338	ns
	-1	0.55	3.39	0.04	1.23	0.39	3.45	3.27	1.83	1.86	5.58	5.392	ns
16 mA	STD	0.64	3.75	0.05	1.45	0.46	1.85	1.69	3.76	3.97	3.06	2.926	ns
	-1	0.55	3.19	0.04	1.23	0.39	1.85	1.69	3.20	3.38	3.06	2.929	ns
24 mA	STD	0.64	3.45	0.05	1.45	0.46	1.70	1.35	3.84	4.47	2.92	2.585	ns
	-1	0.55	2.94	0.04	1.23	0.39	1.71	1.35	3.27	3.80	2.92	2.586	ns

Notes:

1. Software default selection highlighted in gray.
2. For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

Table 2-47 • 2.5 V LVCMOS Low Slew

Automotive-Case Conditions: $T_J = 135^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$, Worst-Case $V_{CCI} = 2.3\text{ V}$
Applicable to Advanced I/O Banks

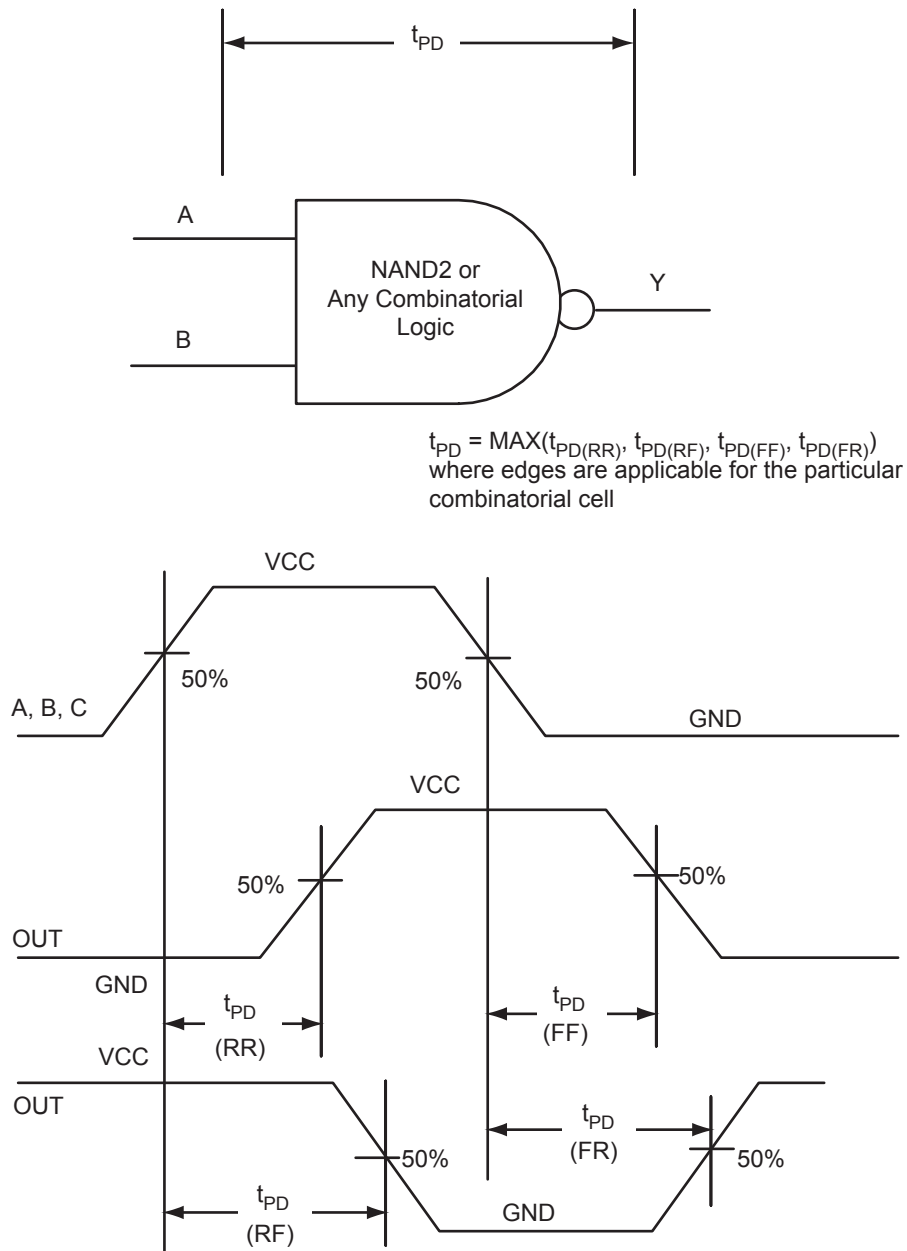
Drive Strength	Speed Grade	t_{DOUT}	t_{DP}	t_{DIN}	t_{PY}	t_{EOUT}	t_{ZL}	t_{ZH}	t_{LZ}	t_{HZ}	t_{ZLS}	t_{ZHS}	Units
2 mA	STD	0.64	12.12	0.05	1.45	0.46	12.54	12.74	1.48	1.19	15.04	15.243	ns
	-1	0.55	10.31	0.04	1.23	0.39	10.67	10.84	1.48	1.20	12.80	12.966	ns
6 mA	STD	0.64	8.24	0.05	1.45	0.46	9.07	8.74	1.68	1.57	11.57	11.237	ns
	-1	0.55	7.01	0.04	1.23	0.39	7.71	7.43	1.69	1.57	9.84	9.559	ns
12 mA	STD	0.64	6.91	0.05	1.45	0.46	7.04	6.62	1.82	1.80	9.54	9.117	ns
	-1	0.55	5.88	0.04	1.23	0.39	5.99	5.63	1.83	1.80	8.11	7.756	ns
16 mA	STD	0.64	6.44	0.05	1.45	0.46	6.56	6.18	1.86	1.86	9.06	8.678	ns
	-1	0.55	5.48	0.04	1.23	0.39	5.58	5.26	1.86	1.86	7.71	7.382	ns
24 mA	STD	0.64	6.16	0.05	1.45	0.46	6.15	6.16	1.90	2.10	8.65	8.657	ns
	-1	0.55	5.24	0.04	1.23	0.39	5.23	5.24	1.90	2.10	7.36	7.364	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

Table 2-100 • Input DDR Propagation Delays
Automotive-Case Conditions: $T_J = 115^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1	Std.	Units
t_{DDRICKQ1}	Clock-to-Out Out_QR for Input DDR	0.33	0.38	ns
t_{DDRICKQ2}	Clock-to-Out Out_QF for Input DDR	0.46	0.54	ns
t_{DDRISUD}	Data Setup for Input DDR	0.34	0.40	ns
t_{DDRILD}	Data Hold for Input DDR	0.00	0.00	ns
$t_{\text{DDRICKR2Q1}}$	Asynchronous Clear-to-Out Out_QR for Input DDR	0.55	0.65	ns
$t_{\text{DDRICKR2Q2}}$	Asynchronous Clear-to-Out Out_QF for Input DDR	0.68	0.80	ns
$t_{\text{DDRIREMCLR}}$	Asynchronous Clear Removal Time for Input DDR	0.00	0.00	ns
$t_{\text{DDRIRECCLR}}$	Asynchronous Clear Recovery Time for Input DDR	0.27	0.31	ns
$t_{\text{DDRILWCLR}}$	Asynchronous Clear Minimum Pulse Width for Input DDR	0.25	0.30	ns
$t_{\text{DDRICKMPWH}}$	Clock Minimum Pulse Width High for Input DDR	0.41	0.48	ns
$t_{\text{DDRICKMPWL}}$	Clock Minimum Pulse Width Low for Input DDR	0.37	0.43	ns
F_{DDRIMAX}	Maximum Frequency for Input DDR	309	263	MHz

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.


Figure 2-25 • Timing Model and Waveforms

Timing Characteristics

Table 2-104 • Combinatorial Cell Propagation Delays
Automotive-Case Conditions: $T_J = 135^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Combinatorial Cell	Equation	Parameter	-1	Std.	Units
INV	$Y = !A$	t_{PD}	0.49	0.57	ns
AND2	$Y = A \cdot B$	t_{PD}	0.57	0.67	ns
NAND2	$Y = !(A \cdot B)$	t_{PD}	0.57	0.67	ns
OR2	$Y = A + B$	t_{PD}	0.59	0.69	ns
NOR2	$Y = !(A + B)$	t_{PD}	0.59	0.69	ns
XOR2	$Y = A \oplus B$	t_{PD}	0.90	1.05	ns
MAJ3	$Y = \text{MAJ}(A, B, C)$	t_{PD}	0.85	1.00	ns
XOR3	$Y = A \oplus B \oplus C$	t_{PD}	1.06	1.25	ns
MUX2	$Y = A !S + B S$	t_{PD}	0.62	0.72	ns
AND3	$Y = A \cdot B \cdot C$	t_{PD}	0.68	0.80	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

Table 2-105 • Combinatorial Cell Propagation Delays
Automotive-Case Conditions: $T_J = 115^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Combinatorial Cell	Equation	Parameter	-1	Std.	Units
INV	$Y = !A$	t_{PD}	0.48	0.56	ns
AND2	$Y = A \cdot B$	t_{PD}	0.56	0.66	ns
NAND2	$Y = !(A \cdot B)$	t_{PD}	0.56	0.66	ns
OR2	$Y = A + B$	t_{PD}	0.58	0.68	ns
NOR2	$Y = !(A + B)$	t_{PD}	0.58	0.68	ns
XOR2	$Y = A \oplus B$	t_{PD}	0.88	1.03	ns
MAJ3	$Y = \text{MAJ}(A, B, C)$	t_{PD}	0.83	0.98	ns
XOR3	$Y = A \oplus B \oplus C$	t_{PD}	1.04	1.23	ns
MUX2	$Y = A !S + B S$	t_{PD}	0.60	0.71	ns
AND3	$Y = A \cdot B \cdot C$	t_{PD}	0.67	0.79	ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

Global Tree Timing Characteristics

Global clock delays include the central rib delay, the spine delay, and the row delay. Delays do not include I/O input buffer clock delays, as these are I/O standard-dependent, and the clock may be driven and conditioned internally by the CCC module. For more details on clock conditioning capabilities, refer to the "Clock Conditioning Circuits" section on page 2-80. Table 2-114 on page 2-79 to Table 2-125 on page 2-97 present minimum and maximum global clock delays within each device. Minimum and maximum delays are measured with minimum and maximum loading.

Timing Characteristics

Table 2-108 • A3P060 Global Resource

Commercial-Case Conditions: $T_J = 135^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	0.87	1.16	1.02	1.37	ns
t_{RCKH}	Input High Delay for Global Clock	0.86	1.20	1.01	1.42	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	0.80		0.94		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	0.98		1.15		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.35		0.41	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-5 on page 2-5 for derating values.

Table 2-109 • A3P060 Global Resource

Commercial-Case Conditions: $T_J = 115^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	0.85	1.13	1.00	1.33	ns
t_{RCKH}	Input High Delay for Global Clock	0.84	1.18	0.99	1.38	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	0.80		0.94		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	0.98		1.15		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.34		0.40	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-5 on page 2-5 for derating values.

Table 2-110 • A3P125 Global Resource
Commercial-Case Conditions: $T_J = 135^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	0.93	1.22	1.09	1.43	ns
t_{RCKH}	Input High Delay for Global Clock	0.92	1.26	1.08	1.49	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	0.80		0.94		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	0.98		1.15		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.35		0.41	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

Table 2-111 • A3P125 Global Resource
Commercial-Case Conditions: $T_J = 115^{\circ}\text{C}$, $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1		Std.		Units
		Min. ¹	Max. ²	Min. ¹	Max. ²	
t_{RCKL}	Input Low Delay for Global Clock	0.90	1.19	1.06	1.40	ns
t_{RCKH}	Input High Delay for Global Clock	0.90	1.23	1.05	1.45	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	0.80		0.94		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	0.98		1.15		ns
t_{RCKSW}	Maximum Skew for Global Clock		0.34		0.40	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

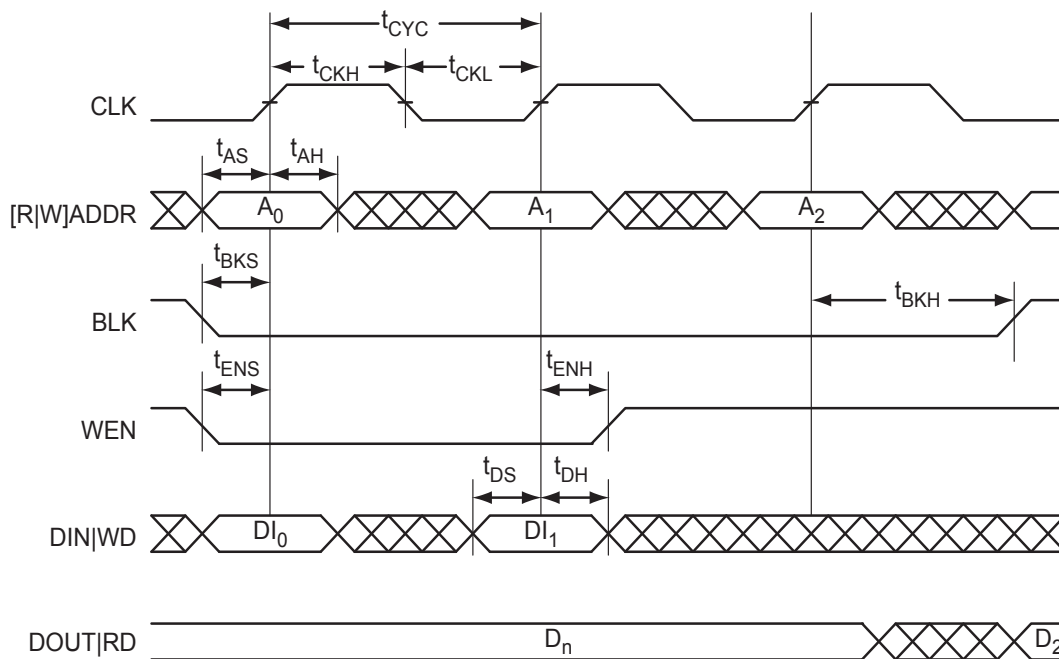


Figure 2-33 • RAM Write, Output Retained. Applicable to Both RAM4K9 and RAM512x18.

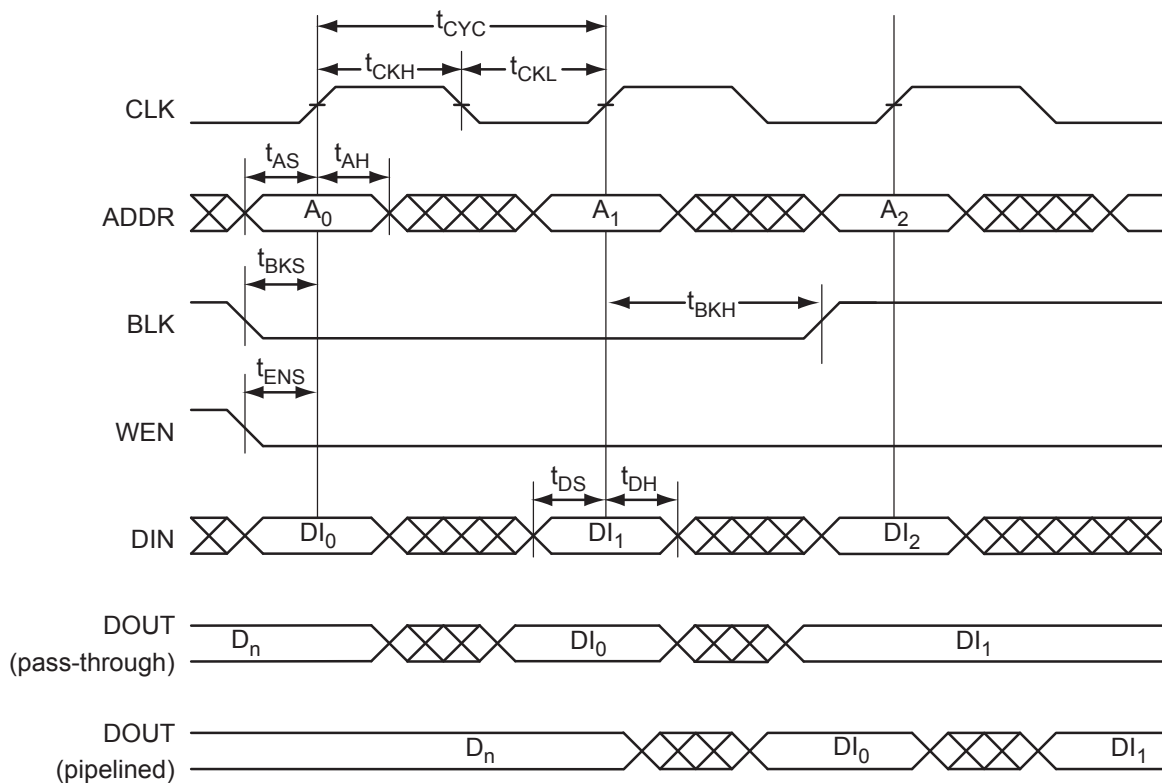


Figure 2-34 • RAM Write, Output as Write Data (WMODE = 1). Applicable to RAM4K9 Only.

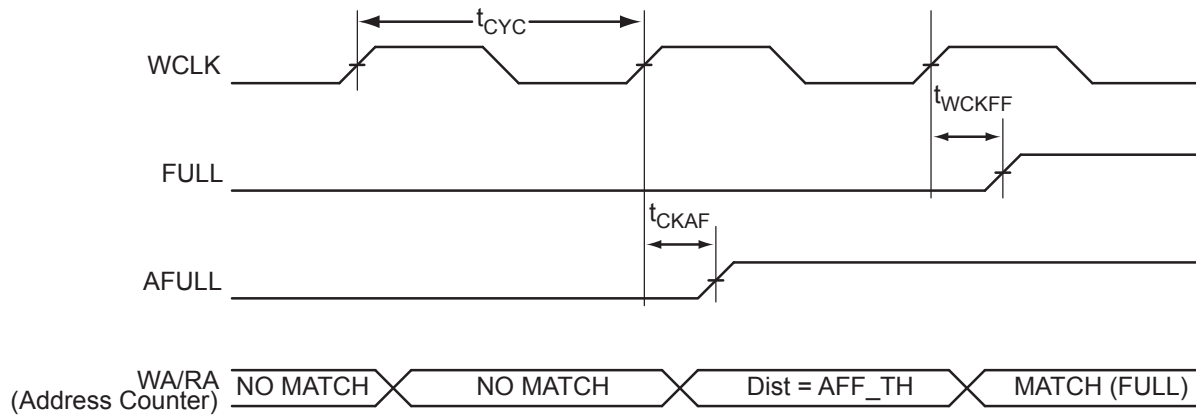
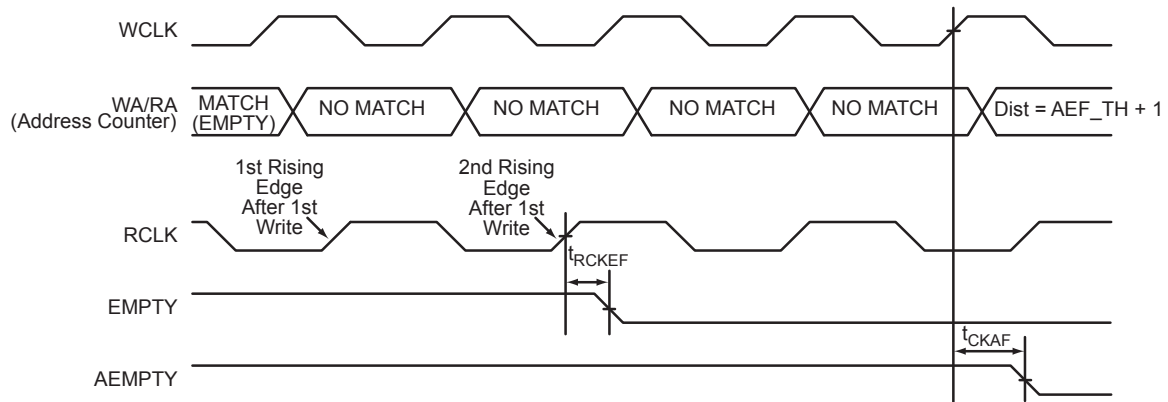
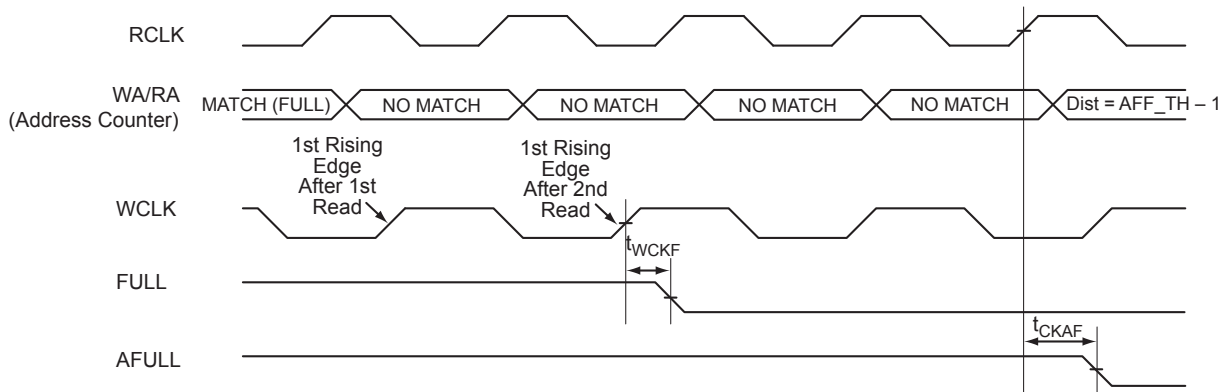
Timing Characteristics

Table 2-117 • RAM4K9
Automotive-Case Conditions: $T_J = 135^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	–1	Std.	Units
t_{AS}	Address Setup Time	0.30	0.36	ns
t_{AH}	Address Hold Time	0.00	0.00	ns
t_{ENS}	REN, WEN Setup Time	0.17	0.20	ns
t_{ENH}	REN, WEN Hold Time	0.12	0.14	ns
t_{BKS}	BLK Setup Time	0.28	0.33	ns
t_{BKH}	BLK Hold Time	0.02	0.03	ns
t_{DS}	Input Data (DIN) Setup Time	0.22	0.26	ns
t_{DH}	Input Data (DIN) Hold Time	0.00	0.00	ns
t_{CKQ1}	Clock High to New Data Valid on DOUT (output retained, WMODE = 0)	2.17	2.55	ns
	Clock High to New Data Valid on DOUT (flow-through, WMODE = 1)	2.86	3.37	ns
t_{CKQ2}	Clock High to New Data Valid on DOUT (pipelined)	1.09	1.28	ns
t_{C2CWWL}^1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Closing Edge	0.28	0.33	ns
t_{C2CWWH}^1	Address collision clk-to-clk delay for reliable write after write on same address—Applicable to Rising Edge	0.26	0.30	ns
t_{C2CRWH}^1	Address collision clk-to-clk delay for reliable read access after write on same address—Applicable to Opening Edge	0.38	0.45	ns
t_{C2CWRH}^1	Address collision clk-to-clk delay for reliable write access after read on same address—Applicable to Opening Edge	0.42	0.49	ns
t_{RSTBQ}	RESET Low to Data Out Low on DO (flow-through)	1.12	1.32	ns
	RESET Low to Data Out Low on DO (pipelined)	1.12	1.32	ns
$t_{REMRSTB}$	RESET Removal	0.35	0.41	ns
$t_{RECRSTB}$	RESET Recovery	1.82	2.14	ns
$t_{MPWRSTB}$	RESET Minimum Pulse Width	0.26	0.30	ns
t_{CYC}	Clock Cycle Time	3.93	4.62	ns
F_{MAX}	Maximum Frequency	255	217	MHz

Notes:

1. For more information, refer to the application note [Simultaneous Read-Write Operations in Dual-Port SRAM for Flash-Based cSoCs and FPGAs](#).
2. For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.


Figure 2-41 • FIFO FULL Flag and AFULL Flag Assertion

Figure 2-42 • FIFO EMPTY Flag and AEMPTY Flag Deassertion

Figure 2-43 • FIFO FULL Flag and AFULL Flag Deassertion

JTAG 1532 Characteristics

JTAG timing delays do not include JTAG I/Os. To obtain complete JTAG timing, add I/O buffer delays to the corresponding standard selected; refer to the I/O timing characteristics in the ["User I/O Characteristics" section on page 2-12](#) for more details.

Timing Characteristics

Table 2-125 • JTAG 1532

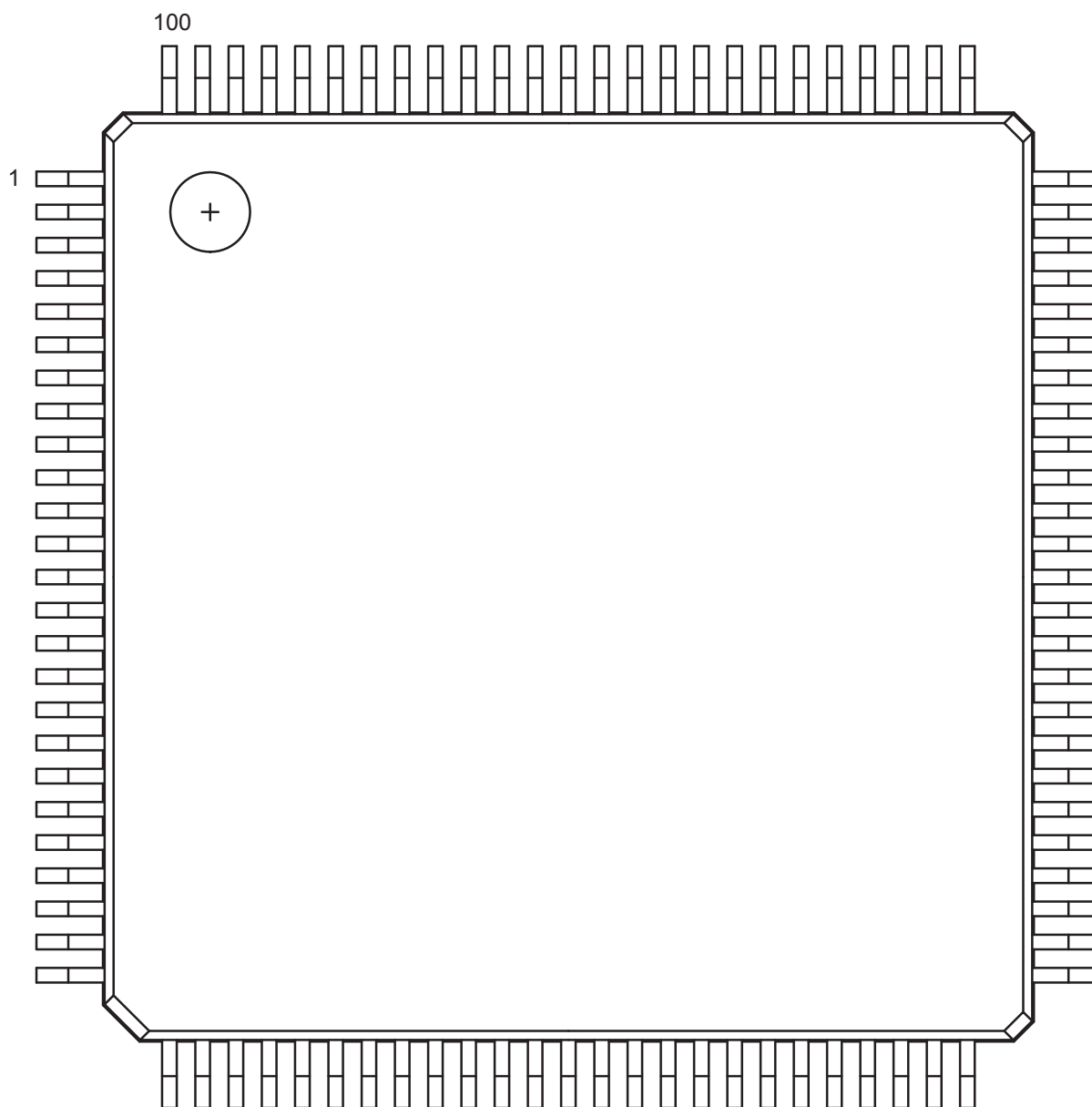
Commercial-Case Conditions: $T_J = 70^{\circ}\text{C}$, Worst-Case $V_{CC} = 1.425\text{ V}$

Parameter	Description	-2	-1	Std.	Units
t_{DISU}	Test Data Input Setup Time				ns
t_{DIHD}	Test Data Input Hold Time				ns
t_{TMSSU}	Test Mode Select Setup Time				ns
t_{TMDHD}	Test Mode Select Hold Time				ns
t_{TCK2Q}	Clock to Q (data out)				ns
t_{RSTB2Q}	Reset to Q (data out)				ns
F_{TCKMAX}	TCK Maximum Frequency	20	20	20	MHz
t_{TRSTREM}	ResetB Removal Time				ns
t_{TRSTREC}	ResetB Recovery Time				ns
t_{TRSTMPW}	ResetB Minimum Pulse				ns

Note: For specific junction temperature and voltage supply levels, refer to [Table 2-5 on page 2-5](#) for derating values.

4 – Package Pin Assignments

VQ100



Note: This is the top view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.actel.com/products/solutions/package/docs.aspx>.

VQ100	
Pin Number	A3P125 Function
1	GND
2	GAA2/IO67RSB1
3	IO68RSB1
4	GAB2/IO69RSB1
5	IO132RSB1
6	GAC2/IO131RSB1
7	IO130RSB1
8	IO129RSB1
9	GND
10	GFB1/IO124RSB1
11	GFB0/IO123RSB1
12	VCOMPLF
13	GFA0/IO122RSB1
14	VCCPLF
15	GFA1/IO121RSB1
16	GFA2/IO120RSB1
17	VCC
18	VCCIB1
19	GEC0/IO111RSB1
20	GEB1/IO110RSB1
21	GEB0/IO109RSB1
22	GEA1/IO108RSB1
23	GEA0/IO107RSB1
24	VMV1
25	GNDQ
26	GEA2/IO106RSB1
27	GEB2/IO105RSB1
28	GEC2/IO104RSB1
29	IO102RSB1
30	IO100RSB1
31	IO99RSB1
32	IO97RSB1
33	IO96RSB1
34	IO95RSB1
35	IO94RSB1
36	IO93RSB1

VQ100	
Pin Number	A3P125 Function
37	VCC
38	GND
39	VCCIB1
40	IO87RSB1
41	IO84RSB1
42	IO81RSB1
43	IO75RSB1
44	GDC2/IO72RSB1
45	GDB2/IO71RSB1
46	GDA2/IO70RSB1
47	TCK
48	TDI
49	TMS
50	VMV1
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO65RSB0
58	GDC0/IO62RSB0
59	GDC1/IO61RSB0
60	GCC2/IO59RSB0
61	GCB2/IO58RSB0
62	GCA0/IO56RSB0
63	GCA1/IO55RSB0
64	GCC0/IO52RSB0
65	GCC1/IO51RSB0
66	VCCIB0
67	GND
68	VCC
69	IO47RSB0
70	GBC2/IO45RSB0
71	GBB2/IO43RSB0
72	IO42RSB0

VQ100	
Pin Number	A3P125 Function
73	GBA2/IO41RSB0
74	VMV0
75	GNDQ
76	GBA1/IO40RSB0
77	GBA0/IO39RSB0
78	GBB1/IO38RSB0
79	GBB0/IO37RSB0
80	GBC1/IO36RSB0
81	GBC0/IO35RSB0
82	IO32RSB0
83	IO28RSB0
84	IO25RSB0
85	IO22RSB0
86	IO19RSB0
87	VCCIB0
88	GND
89	VCC
90	IO15RSB0
91	IO13RSB0
92	IO11RSB0
93	IO09RSB0
94	IO07RSB0
95	GAC1/IO05RSB0
96	GAC0/IO04RSB0
97	GAB1/IO03RSB0
98	GAB0/IO02RSB0
99	GAA1/IO01RSB0
100	GAA0/IO00RSB0

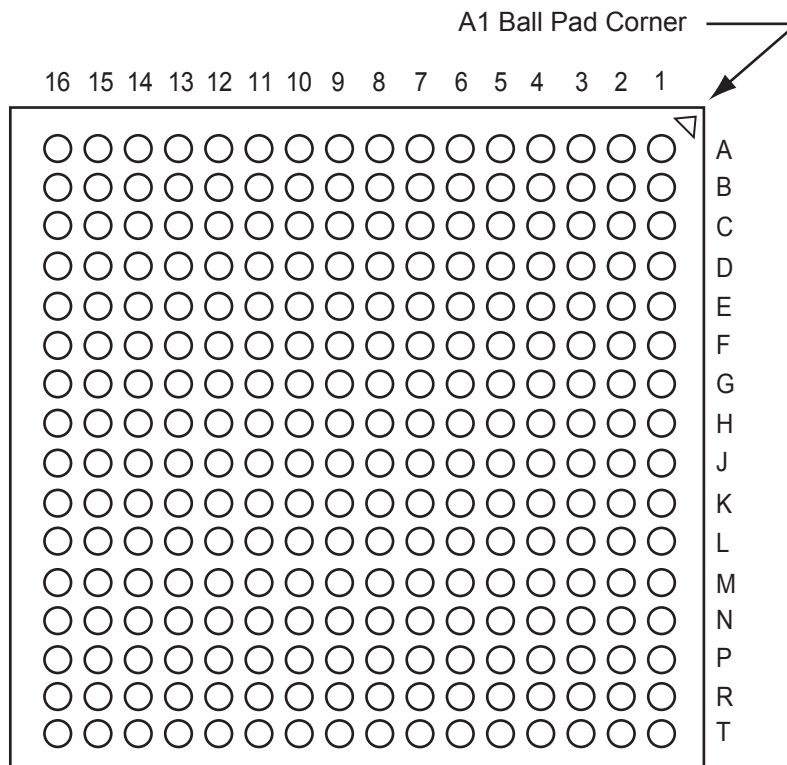
FG144	
Pin Number	A3P125 Function
K1	GEB0/IO109RSB1
K2	GEA1/IO108RSB1
K3	GEA0/IO107RSB1
K4	GEA2/IO106RSB1
K5	IO100RSB1
K6	IO98RSB1
K7	GND
K8	IO73RSB1
K9	GDC2/IO72RSB1
K10	GND
K11	GDA0/IO66RSB0
K12	GDB0/IO64RSB0
L1	GND
L2	VMV1
L3	GEB2/IO105RSB1
L4	IO102RSB1
L5	VCCIB1
L6	IO95RSB1
L7	IO85RSB1
L8	IO74RSB1
L9	TMS
L10	VJTAG
L11	VMV1
L12	TRST
M1	GNDQ
M2	GEC2/IO104RSB1
M3	IO103RSB1
M4	IO101RSB1
M5	IO97RSB1
M6	IO94RSB1
M7	IO86RSB1
M8	IO75RSB1
M9	TDI
M10	VCCIB1
M11	VPUMP
M12	GNDQ

FG144	
Pin Number	A3P1000 Function
A1	GNDQ
A2	VMV0
A3	GAB0/IO02RSB0
A4	GAB1/IO03RSB0
A5	IO10RSB0
A6	GND
A7	IO44RSB0
A8	VCC
A9	IO69RSB0
A10	GBA0/IO76RSB0
A11	GBA1/IO77RSB0
A12	GNDQ
B1	GAB2/IO224PDB3
B2	GND
B3	GAA0/IO00RSB0
B4	GAA1/IO01RSB0
B5	IO13RSB0
B6	IO26RSB0
B7	IO35RSB0
B8	IO60RSB0
B9	GBB0/IO74RSB0
B10	GBB1/IO75RSB0
B11	GND
B12	VMV1
C1	IO224NDB3
C2	GFA2/IO206PPB3
C3	GAC2/IO223PDB3
C4	VCC
C5	IO16RSB0
C6	IO29RSB0
C7	IO32RSB0
C8	IO63RSB0
C9	IO66RSB0
C10	GBA2/IO78PDB1
C11	IO78NDB1
C12	GBC2/IO80PPB1

FG144	
Pin Number	A3P1000 Function
D1	IO213PDB3
D2	IO213NDB3
D3	IO223NDB3
D4	GAA2/IO225PPB3
D5	GAC0/IO04RSB0
D6	GAC1/IO05RSB0
D7	GBC0/IO72RSB0
D8	GBC1/IO73RSB0
D9	GBB2/IO79PDB1
D10	IO79NDB1
D11	IO80NPB1
D12	GCB1/IO92PPB1
E1	VCC
E2	GFC0/IO209NDB3
E3	GFC1/IO209PDB3
E4	VCCIB3
E5	IO225NPB3
E6	VCCIB0
E7	VCCIB0
E8	GCC1/IO91PDB1
E9	VCCIB1
E10	VCC
E11	GCA0/IO93NDB1
E12	IO94NDB1
F1	GFB0/IO208NPB3
F2	VCOMPLF
F3	GFB1/IO208PPB3
F4	IO206NPB3
F5	GND
F6	GND
F7	GND
F8	GCC0/IO91NDB1
F9	GCB0/IO92NPB1
F10	GND
F11	GCA1/IO93PDB1
F12	GCA2/IO94PDB1

FG144	
Pin Number	A3P1000 Function
G1	GFA1/IO207PPB3
G2	GND
G3	VCCPLF
G4	GFA0/IO207NPB3
G5	GND
G6	GND
G7	GND
G8	GDC1/IO111PPB1
G9	IO96NDB1
G10	GCC2/IO96PDB1
G11	IO95NDB1
G12	GCB2/IO95PDB1
H1	VCC
H2	GFB2/IO205PDB3
H3	GFC2/IO204PSB3
H4	GEC1/IO190PDB3
H5	VCC
H6	IO105PDB1
H7	IO105NDB1
H8	GDB2/IO115RSB2
H9	GDC0/IO111NPB1
H10	VCCIB1
H11	IO101PSB1
H12	VCC
J1	GEB1/IO189PDB3
J2	IO205NDB3
J3	VCCIB3
J4	GEC0/IO190NDB3
J5	IO160RSB2
J6	IO157RSB2
J7	VCC
J8	TCK
J9	GDA2/IO114RSB2
J10	TDO
J11	GDA1/IO113PDB1
J12	GDB1/IO112PDB1

FG256



Note: This is the bottom view of the package.

Note

For Package Manufacturing and Environmental information, visit the Resource Center at <http://www.actel.com/products/solutions/package/docs.aspx>.

FG256	
Pin Number	A3P1000 Function
P9	IO137RSB2
P10	IO134RSB2
P11	IO128RSB2
P12	VMV1
P13	TCK
P14	VPUMP
P15	TRST
P16	GDA0/IO113NDB1
R1	GEA1/IO188PDB3
R2	GEA0/IO188NDB3
R3	IO184RSB2
R4	GEC2/IO185RSB2
R5	IO168RSB2
R6	IO163RSB2
R7	IO157RSB2
R8	IO149RSB2
R9	IO143RSB2
R10	IO138RSB2
R11	IO131RSB2
R12	IO125RSB2
R13	GDB2/IO115RSB2
R14	TDI
R15	GNDQ
R16	TDO
T1	GND
T2	IO183RSB2
T3	GEB2/IO186RSB2
T4	IO172RSB2
T5	IO170RSB2
T6	IO164RSB2
T7	IO158RSB2
T8	IO153RSB2
T9	IO142RSB2
T10	IO135RSB2
T11	IO130RSB2
T12	GDC2/IO116RSB2

FG256	
Pin Number	A3P1000 Function
T13	IO120RSB2
T14	GDA2/IO114RSB2
T15	TMS
T16	GND

FG484	
Pin Number	A3P1000 Function
Y15	VCC
Y16	NC
Y17	NC
Y18	GND
Y19	NC
Y20	NC
Y21	NC
Y22	VCCIB1
AA1	GND
AA2	VCCIB3
AA3	NC
AA4	IO181RSB2
AA5	IO178RSB2
AA6	IO175RSB2
AA7	IO169RSB2
AA8	IO166RSB2
AA9	IO160RSB2
AA10	IO152RSB2
AA11	IO146RSB2
AA12	IO139RSB2
AA13	IO133RSB2
AA14	NC
AA15	NC
AA16	IO122RSB2
AA17	IO119RSB2
AA18	IO117RSB2
AA19	NC
AA20	NC
AA21	VCCIB1
AA22	GND
AB1	GND
AB2	GND
AB3	VCCIB2
AB4	IO180RSB2
AB5	IO176RSB2
AB6	IO173RSB2

FG484	
Pin Number	A3P1000 Function
AB7	IO167RSB2
AB8	IO162RSB2
AB9	IO156RSB2
AB10	IO150RSB2
AB11	IO145RSB2
AB12	IO144RSB2
AB13	IO132RSB2
AB14	IO127RSB2
AB15	IO126RSB2
AB16	IO123RSB2
AB17	IO121RSB2
AB18	IO118RSB2
AB19	NC
AB20	VCCIB2
AB21	GND
AB22	GND

Revision	Changes	Page
Revision 2 (continued)	The "Pin Descriptions and Packaging" chapter has been added (SAR 34767),	3-1
	The "VQ100" pin table for A3P125 has been added (SAR 37944).	4-3
	Package names used in the "Package Pin Assignments" section were revised to match standards given in <i>Package Mechanical Drawings</i> (SAR 34767).	4-1
July 2010	The versioning system for datasheets has been changed. Datasheets are assigned a revision number that increments each time the datasheet is revised. The "Automotive ProASIC3 Device Status" table on page II indicates the status for each device in the device family.	N/A

Revision	Changes	Page
Revision 1 (Dec 2009) Product Brief v1.1 Packaging v1.1	The QNG132 package was added to the "Automotive ProASIC3 Product Family" table, "I/Os Per Package" table, "Automotive ProASIC3 Ordering Information", and "Temperature Grade Offerings".	I – IV
	Pin tables for A3P125 and A3P250 were added for the "QN132" package.	4-6